



Introduction to CAD Techniques for Design and Verification

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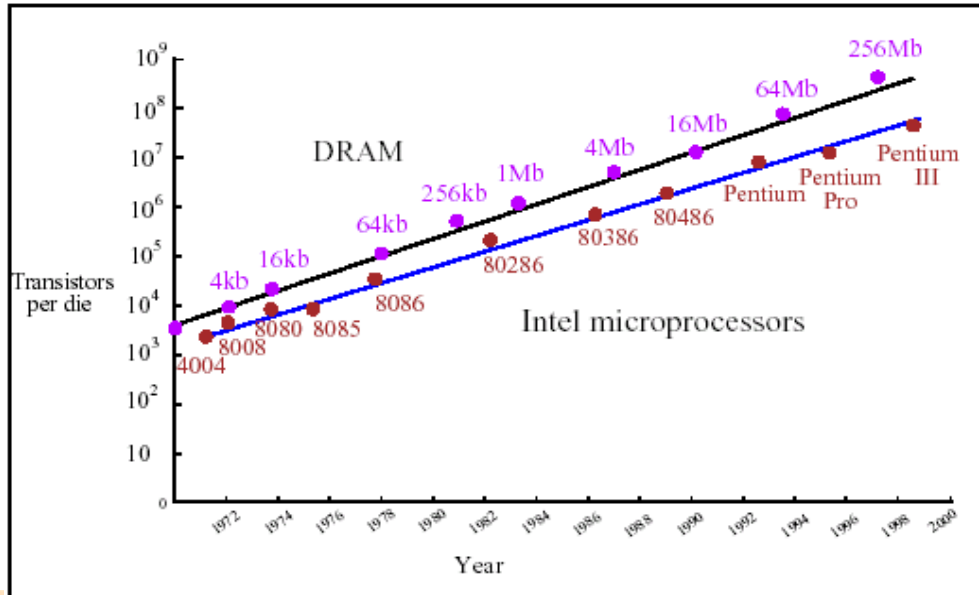
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Outline

- ◆ Moving to SOC
- ◆ CAD in SOC Design
- ◆ Solutions for Verification Problems
- ◆ Solutions for Integration Problems
- ◆ Solutions for DSM Problems

Moore's Law

- ◆ Logic capacity doubles per IC per year at regular intervals (1965)
- ◆ Logic capacity doubles per IC every 18 months (1975)



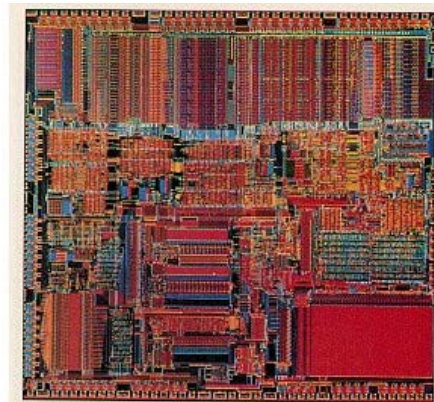
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P.3

The Dies of Intel CPUs



Pentium Pro



386



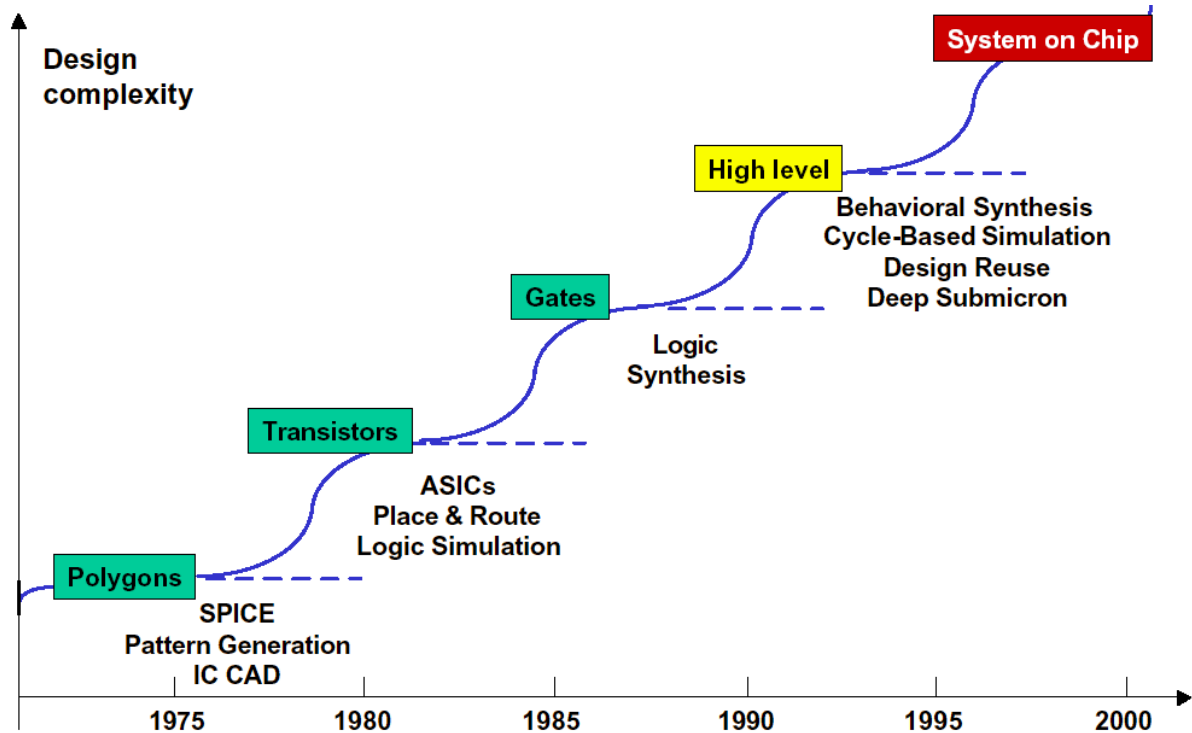
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P.4

Trends of VLSI Design



Reference : www.doulos.com

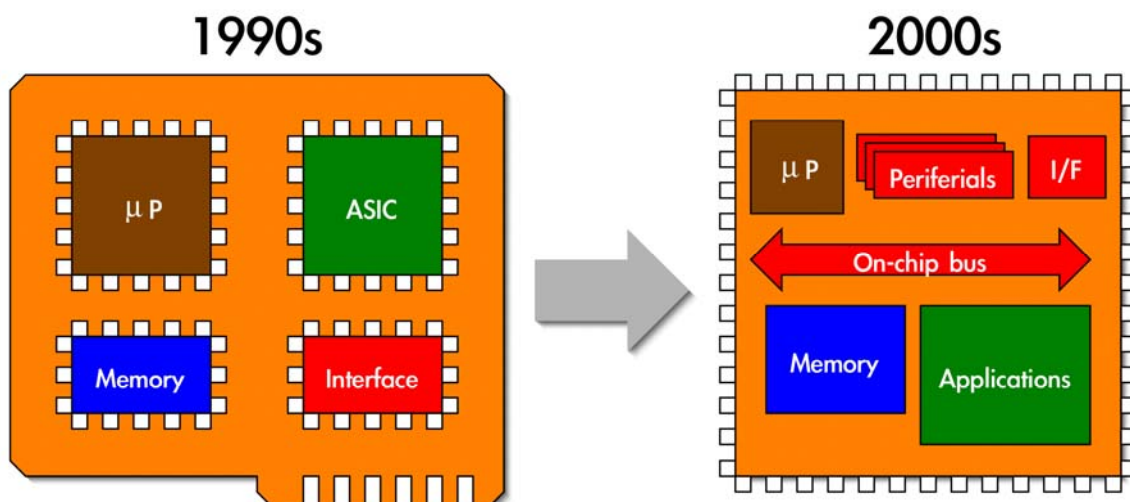


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P.5

What is SoC?

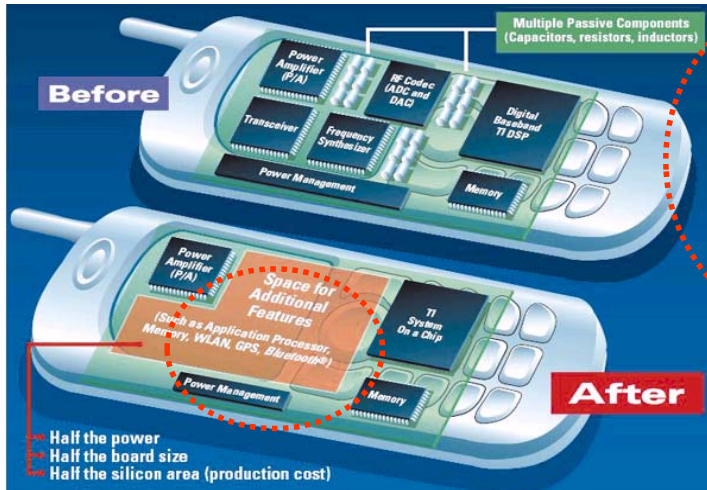
- ◆ System-on-Chip
- ◆ An IC that integrates the major functional elements of a complete end-product into a single chip



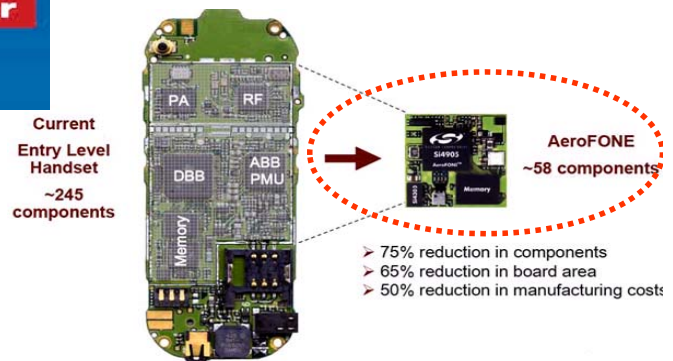
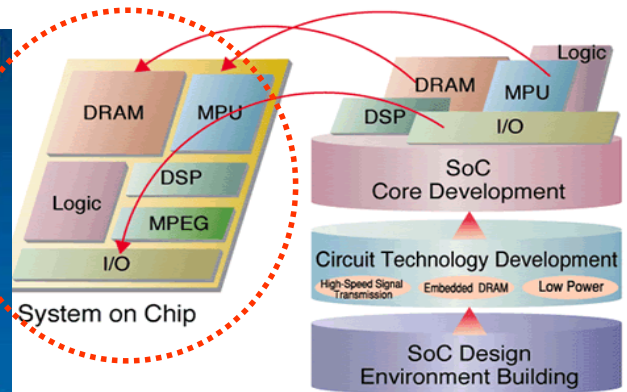
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P.6

Why Highly Integrated Circuits?



除了體積變小之外，耗電、效能、成本表現均較優



資料來源：工研院IEK(2007/09)



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P.7

SoC Challenges

- ◆ Increasing complexity
 - Time-to-market pressure
 - Verification bottleneck
- ◆ Integration
 - Hardware v.s. software
 - Digital circuits v.s. analog circuits
 - Testing issues
- ◆ Deep submicron effects
 - Timing closure problem
 - Signal integrity problem
 - Reliability problem



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Time-to-Market Pressure

- ◆ A lot of pressure from
 - Shorter product lifespan
 - Shrinking design cycles

	1997	1998	1999	2002
Applications	Cellar, PDA, DVD	Set-top boxes, wireless PDA	Internet applications, anything portable	Ubiquitous computing, intelligent, interconnected controllers
Design cycle (month)	18 - 12	12 - 10	10 - 8	8 - 6
Derivative cycle (month)	8 - 6	6 - 4	4 - 2	3 - 2

* Adapted from "Surviving the SOC Revolution."

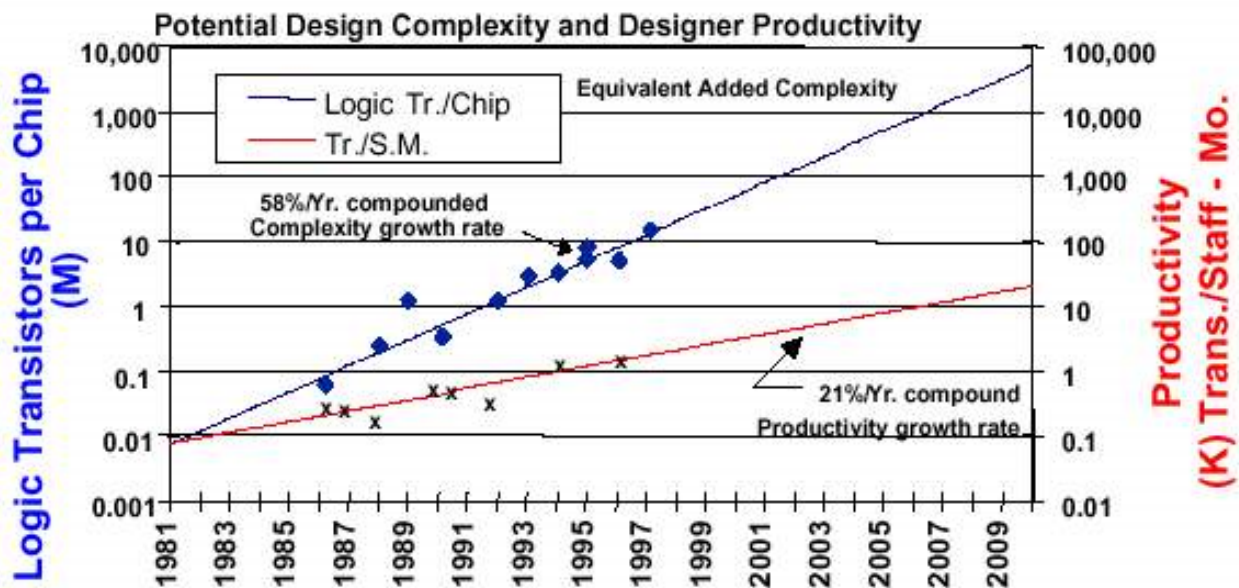


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Productivity Gap

- ◆ We do need more productivity !! ➡ CAD



Source : ITRS Roadmap 1999 Edition, SIA.



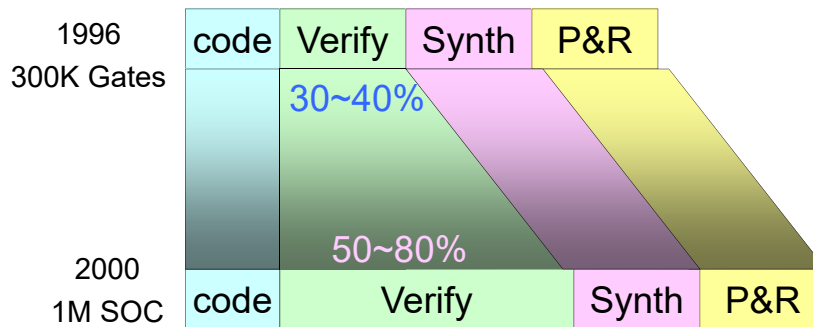
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P.10

Verification Bottleneck

- ◆ Verification becomes the major bottleneck of the modern design flows

➤ From 30%-40% to 50%-80%



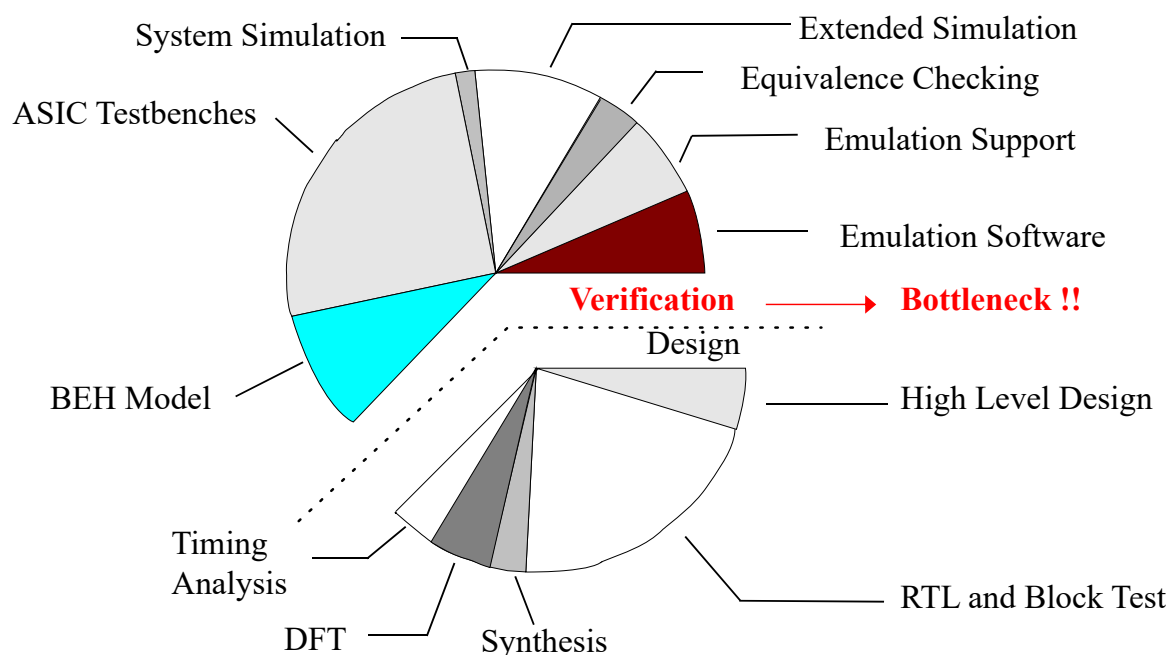
- ◆ An effective verification methodology is also highly desirable



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An Industrial Example



Source : "Functional Verification on Large ASICs"
by Adrian Evans, etc., 35th DAC, June 1998.



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P.12

SoC Challenges

- ◆ Increasing complexity
 - Time-to-market pressure
 - Verification bottleneck
- ◆ **Integration**
 - Hardware v.s. software
 - Digital circuits v.s. analog circuits
 - Testing issues
- ◆ Deep submicron effects
 - Timing closure problem
 - Signal integrity problem
 - Reliability problem

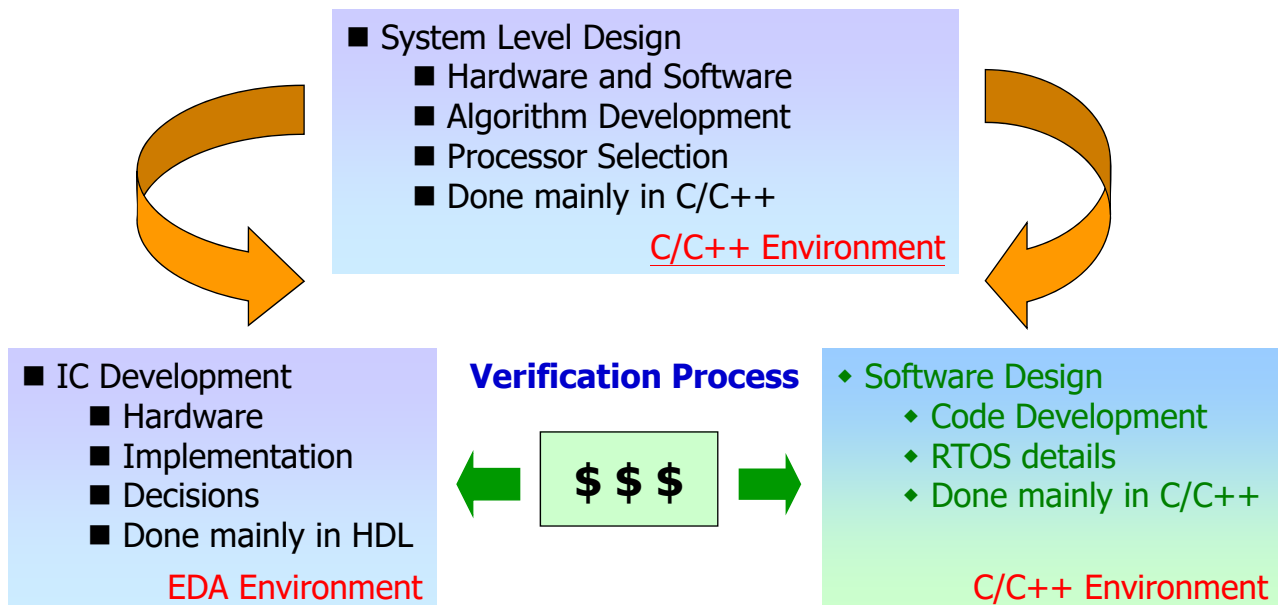


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HW/SW Integration

- ◆ Integrating HW/SW at the final step may require high cost to fix inconsistency problems



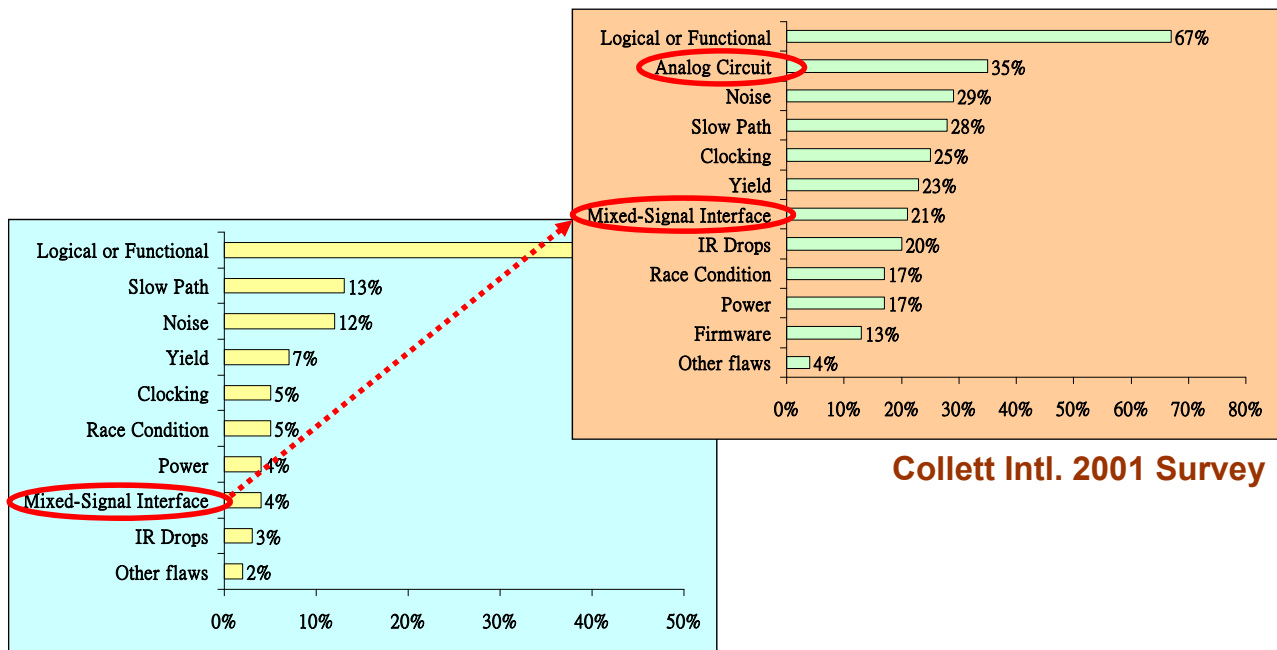
Reference : Synopsys



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Mixed Signals in SoC



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Challenges for MS Designs

- ◆ Design challenges
 - Chip-level simulation takes too much time
 - Design budgets are not distributed in a well-defined manner
 - Too much time is spent on low-level iterations
 - Design is not completely systematic
 - There is limited or no use of HDL
- ◆ Solutions:
 - Use a systematic, top-down design approach to capture design intent
 - Develop some tools for rapid targeting of different design technologies



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SoC Testing Challenges

◆ Distributed design and test

- Core provider does not know the target environment
- System integrator is responsible for manufacturing testing

◆ Test access

- Difficulties to access deeply embedded cores
- Bandwidth, I/O pin count limitations

◆ Test optimization

- Minimizing test cost while satisfying constraints such as power, resources, coverage, etc.



SoC Challenges

◆ Increasing complexity

- Time-to-market pressure
- Verification bottleneck

◆ Integration

- Hardware v.s. software
- Digital circuits v.s. analog circuits
- Testing issues

◆ Deep submicron effects

- Timing closure problem
- Signal integrity problem
- Reliability problem



Nanometer Design Challenges

- ◆ In 2005, feature size $\approx 0.1 \mu\text{m}$, μP frequency $\approx 3.5 \text{ GHz}$, die size $\approx 520 \text{ mm}^2$, μP transistor count per chip $\approx 200\text{M}$, wiring level ≈ 8 layers, supply voltage $\approx 1 \text{ V}$, power consumption $\approx 160 \text{ W}$.
- **Feature size** ↓ → sub-wavelength lithography (impacts of process variation)? noise? wire coupling? reliability?
- **Frequency** ↑, **dimension** ↑ → interconnect delay? electromagnetic field effects? timing closure?
- **Chip complexity** ↑ → large-scale system design methodology?
- **Supply voltage** ↓ → signal integrity (noise, IR drop, etc)?
- **Wiring level** ↑ → manufacturability? 3D layout?
- **Power consumption** ↑ → power & thermal issues?

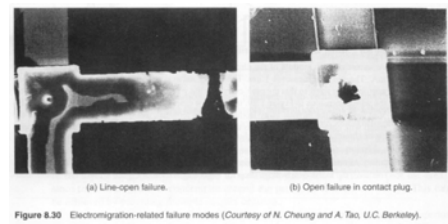
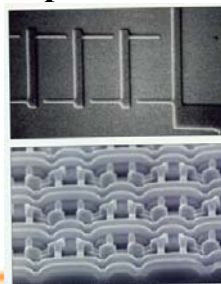
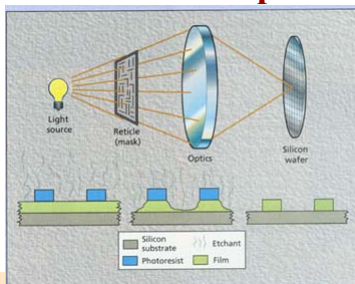


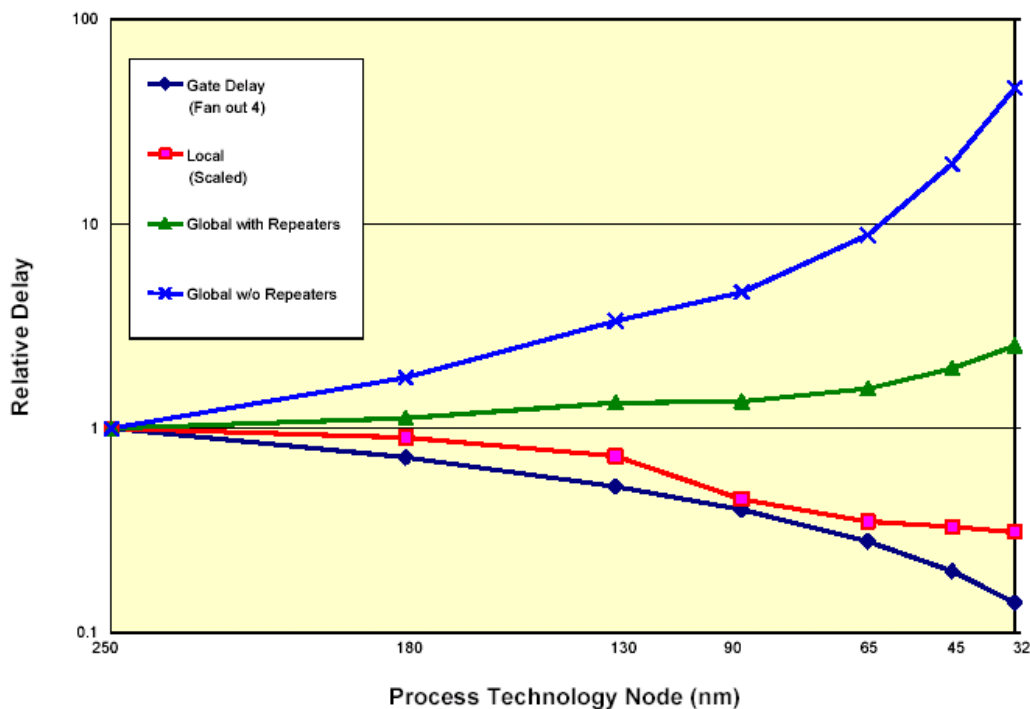
Figure 6.30 Electromigration-related failure modes (Courtesy of N. Cheung and A. Tao, U.C. Berkeley).



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Wiring Delay vs. Feature Size



Source : ITRS 2001



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Timing Closure Problem

- ◆ Wire delay starts to dominate total delay in DSM process
 - Cannot be ignored as taught in digital design course
- ◆ Only statistical wire delay model can be used at design phase
 - Lack of physical information about wire length
- ◆ Incorrect estimations require long iterations to meeting timing
 - Design schedule will be seriously delayed !!

Path name	Pre-layout delay	Post-layout delay
P1	21.72	40.92 (+88.4%)
P2	6.65	7.81 (+17.4%)
P3	11.14	10.43 (-6.4%)
P4	5.03	5.44 (+8.15%)
P5	6.35	13.21 (+108.0%)
P6	6.42	13.20 (+105.6%)



Outline

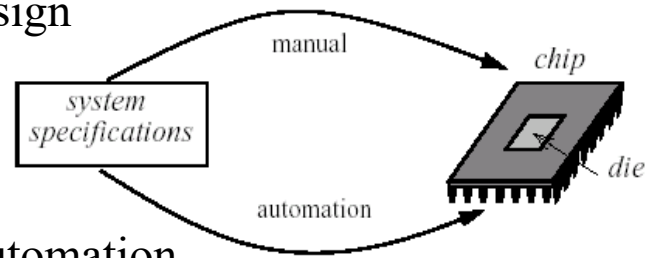
- ◆ Moving to SOC
- ◆ CAD in SOC Design
- ◆ Solutions for Verification Problems
- ◆ Solutions for Integration Problems
- ◆ Solutions for DSM Problems



What is CAD ?

◆ CAD = Computer-Aided Design

- Exist **everywhere** in the whole design flow
- Important but invisible



◆ EDA = Electronic Design Automation

- CAD for electronic industry

◆ Typically, more than **50%** design time is elapsed on running CAD tools

- Meet the time to market → **faster implementation**
- Reduce costs → **less engineers**
- Higher quality → **fewer bugs**
- Managing the complexity → **larger designs**



Human vs. Computer

◆ Computation time

- Human: slow
- Computer: fast

◆ Correctness of results

- Human: not guaranteed
- Computer: always correct

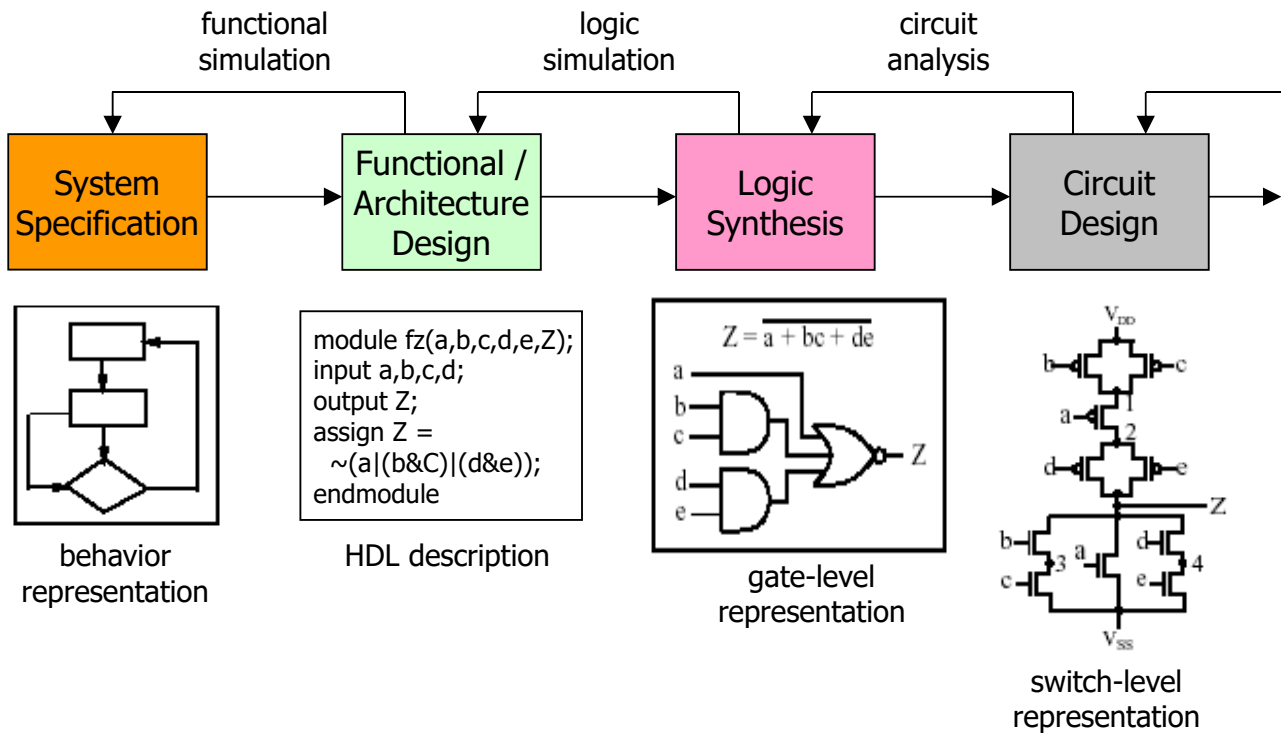
◆ Working hours

- Human: 8hrs / day
- Computer: 24hrs / day

◆ And more and more advantages ...



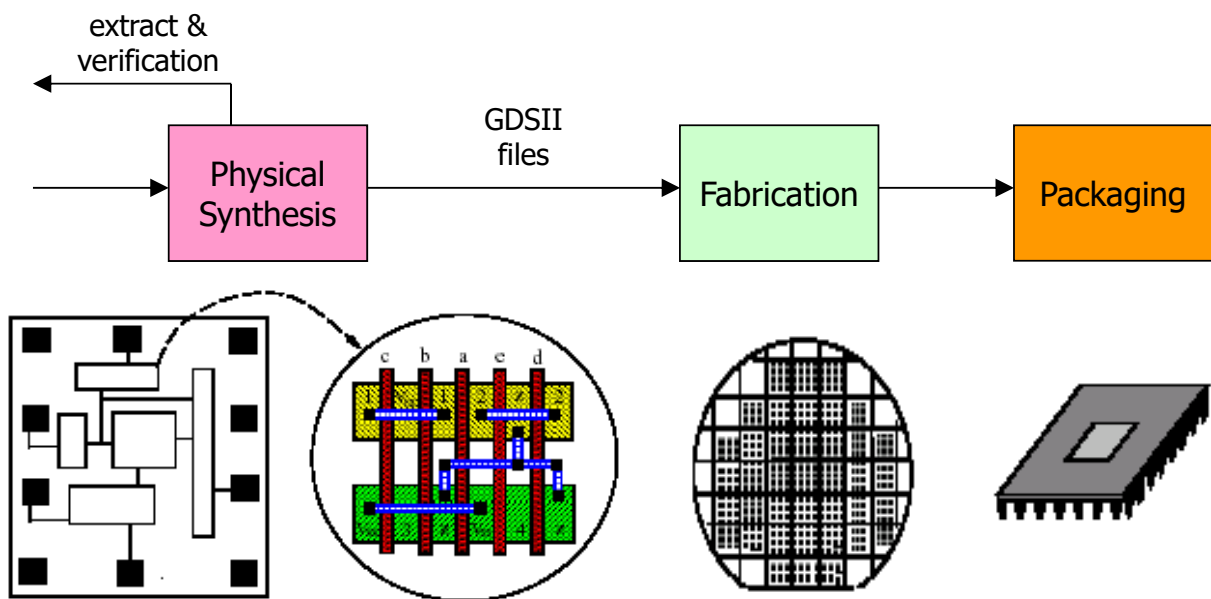
Typical VLSI Design Flow



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P.25

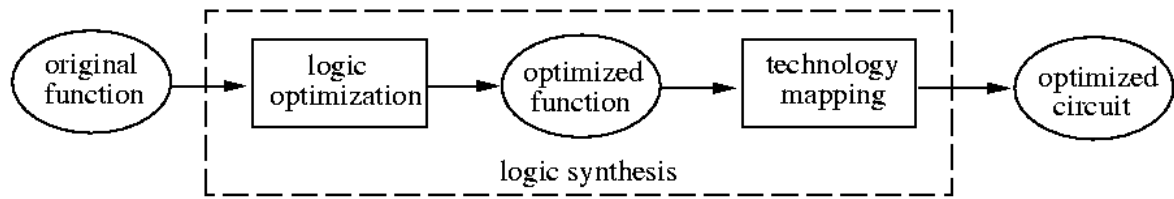
Typical VLSI Design Flow



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Logic Design/Synthesis



- ◆ **Logic synthesis** programs transform Boolean expressions into logic gate networks in a particular library.
 - Optimization goals: minimize area, delay, power, etc
- ◆ **Technology-independent** optimization: logic optimization
 - Optimizes Boolean expression equivalent.
- ◆ **Technology-dependent** optimization: **technology mapping/library binding**
 - Maps Boolean expressions into a particular cell library.

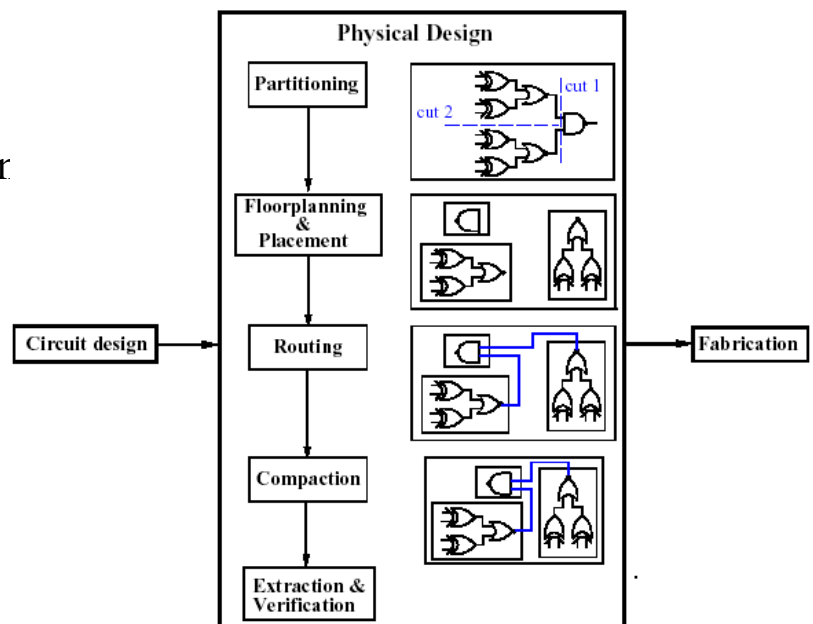


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Physical Design Flow

- ◆ Physical design cycle:
 1. Logic partitioning
 2. Floorplanning, placement, and pin assignment
 3. Routing (global and detailed)
 4. Compaction
 5. RLC extraction & verification

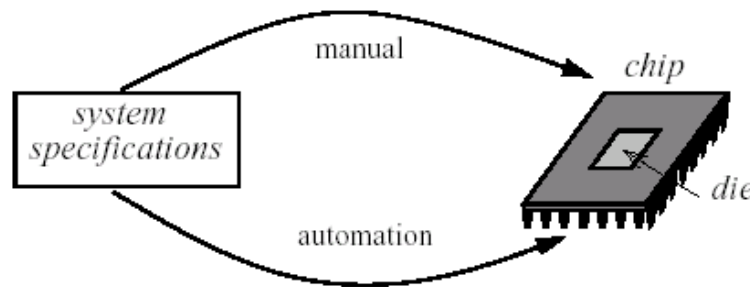


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VLSI Design Considerations

- ◆ Several conflicting considerations
 - **Design complexity**: large number of devices/transistors
 - **Cost**: die area, packing, testing, etc.
 - **Performance**: optimization requirements for high performance
 - **Time-to-market**: about 15% gain for early birds
 - Others: power, noise, testability, reliability, ... etc.
- ◆ Keys: hierarchical design, abstraction, design automation

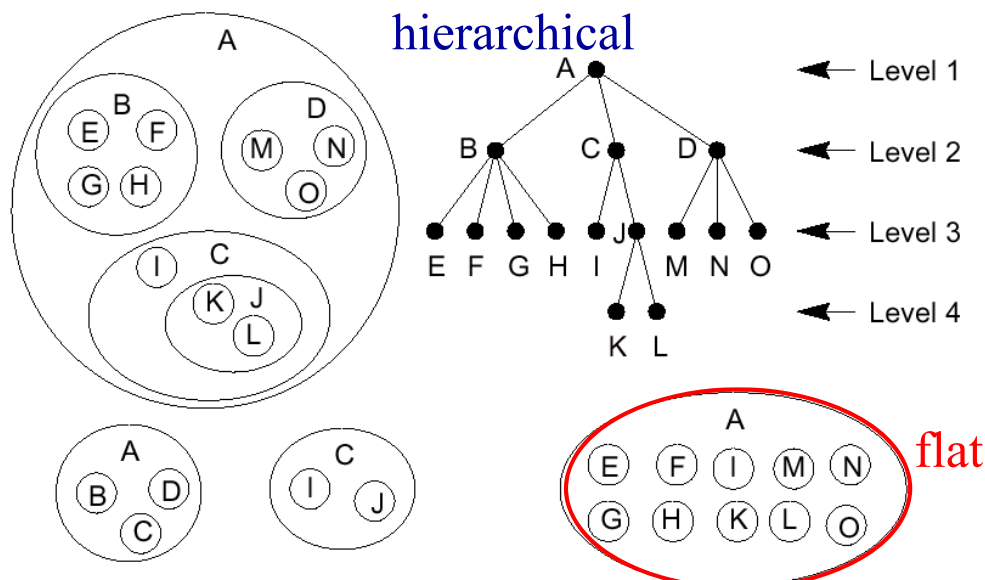


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Hierarchical Design

- ◆ **Hierarchy**: something is composed of simpler things.
- ◆ Design cannot be done in one step \Rightarrow partition the design hierarchically

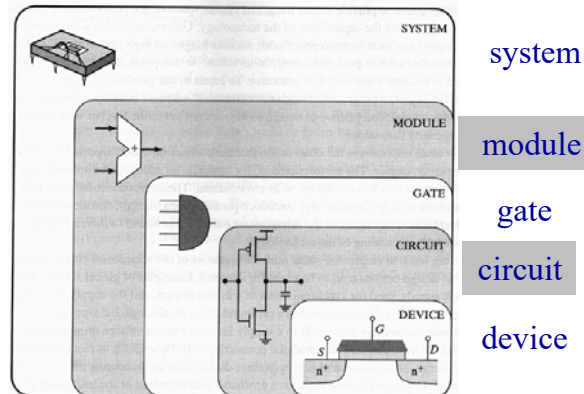


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Abstraction

- ◆ **Abstraction:** when looking at a certain level, you don't need to know all details of the lower levels.



- ◆ Design domains:
 - **Behavioral:** functionality of components
 - **Structural:** connectivity between components
 - **Physical:** layout description
- ◆ Each design domain has its own hierarchy.



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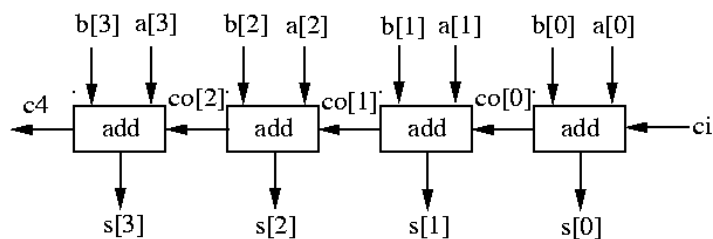
P.31

Three Design Views

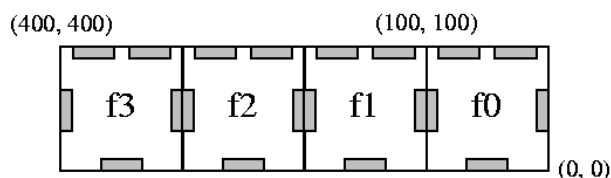
Behavior

```
Module add4 (s, c4, ci, a, b);  
  input [3:0] a, b;  
  input ci;  
  output [3:0] s;  
  output c4;  
  assign {c4,s} = a + b + ci;  
endmodule
```

Structural



Physical

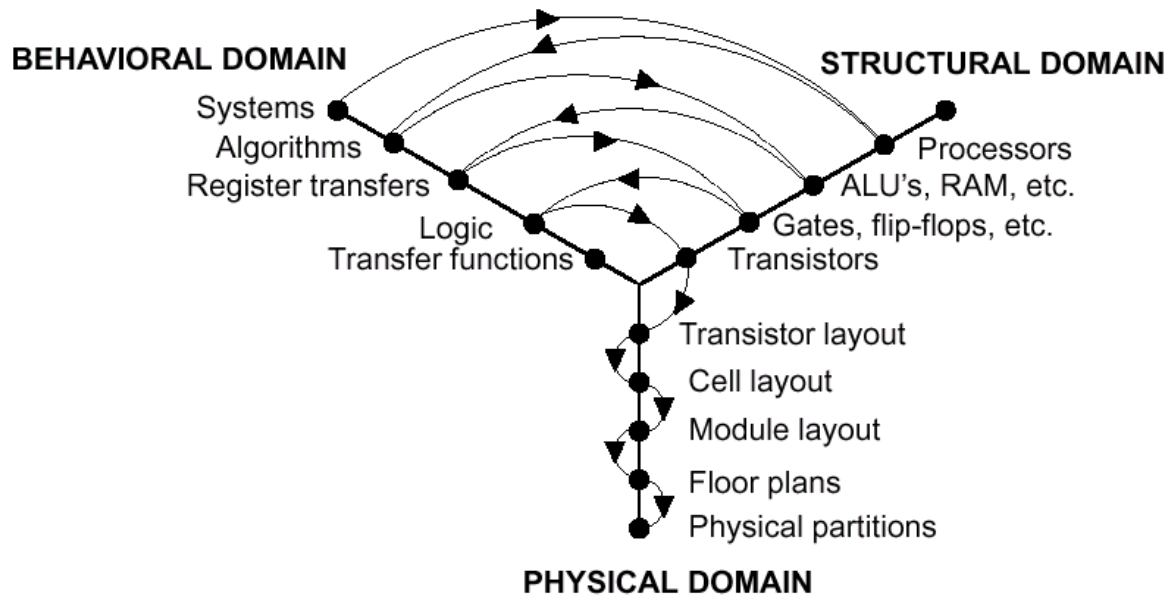


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Top-Down Structural Design

◆ Also known as the Gajski's Y chart

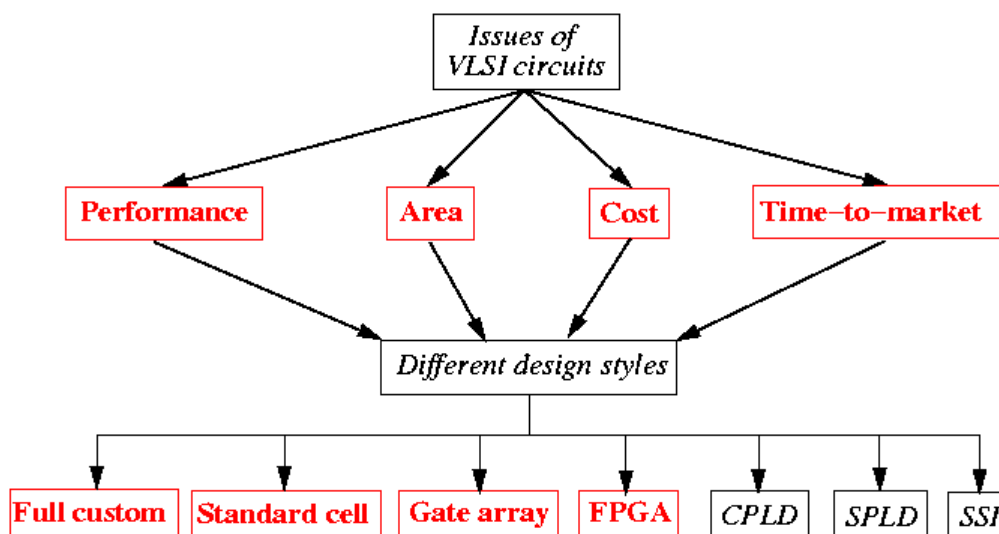


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Design Styles

◆ Specific design styles shall require specific EDA tools



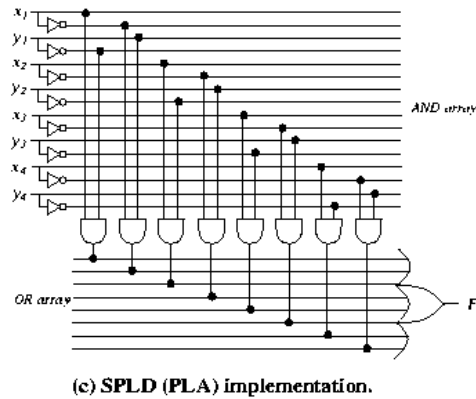
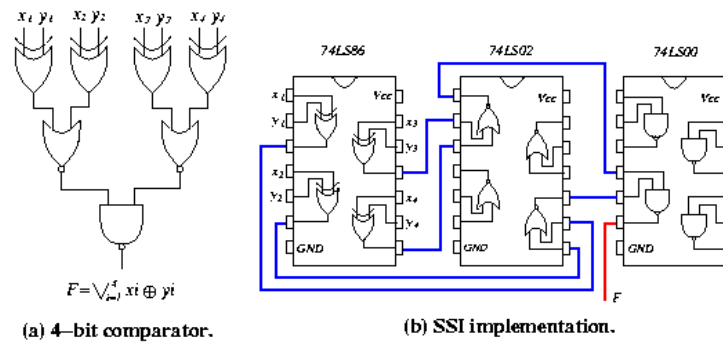
Performance, Area efficiency, Cost, Flexibility



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SSI/SPLD Design Style

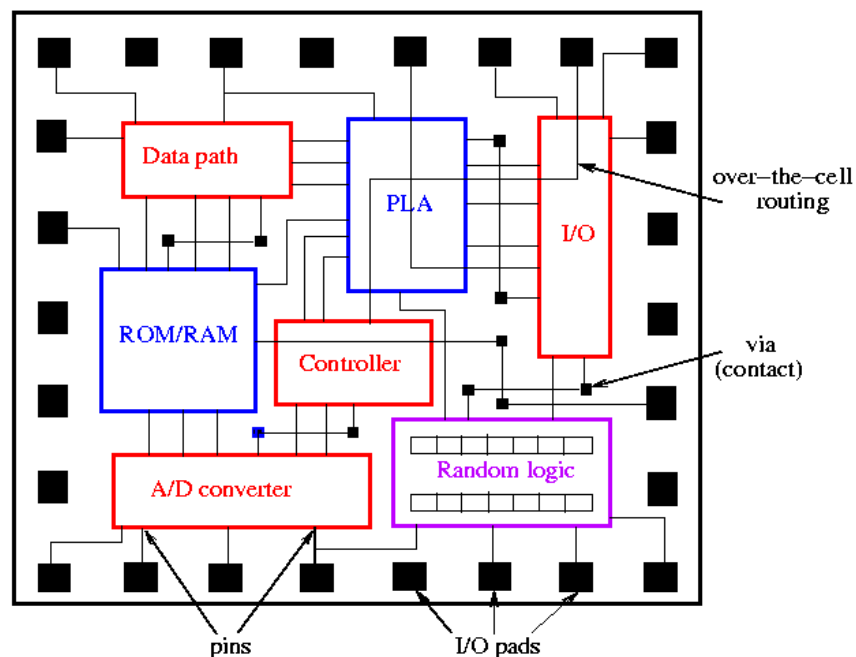


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Full Custom Design Style

- ◆ Designers can control the shape of all mask patterns.
- ◆ Designers can specify the design up to the level of individual transistors.

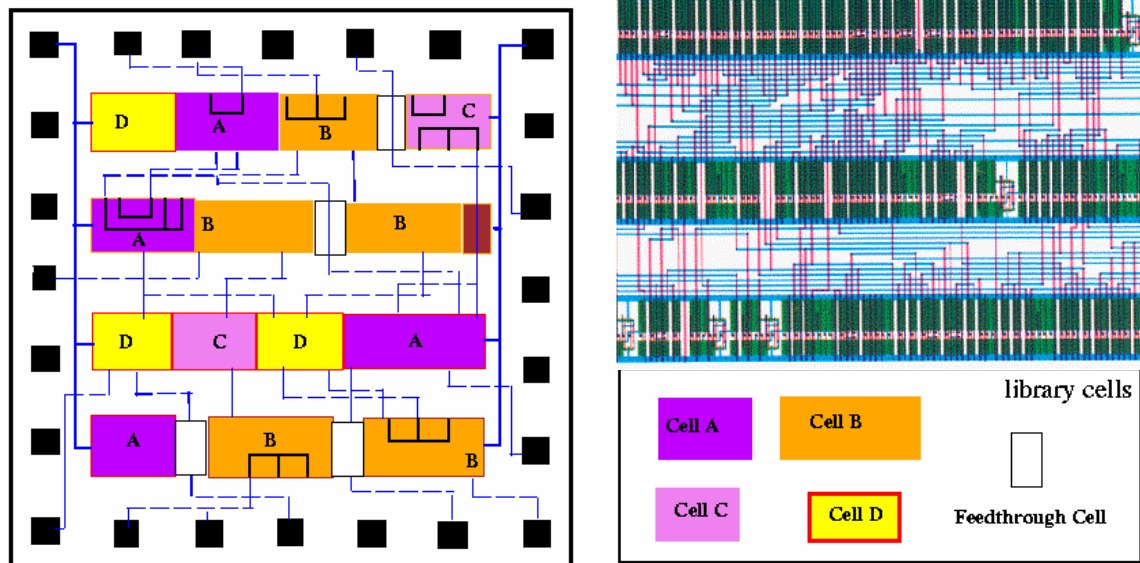


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Standard Cell Design Style

- ◆ Select pre-designed cells (of same height) to implement logic
- ◆ Characterize and store cells in library



Courtesy Newton/Pister, UC-Berkeley

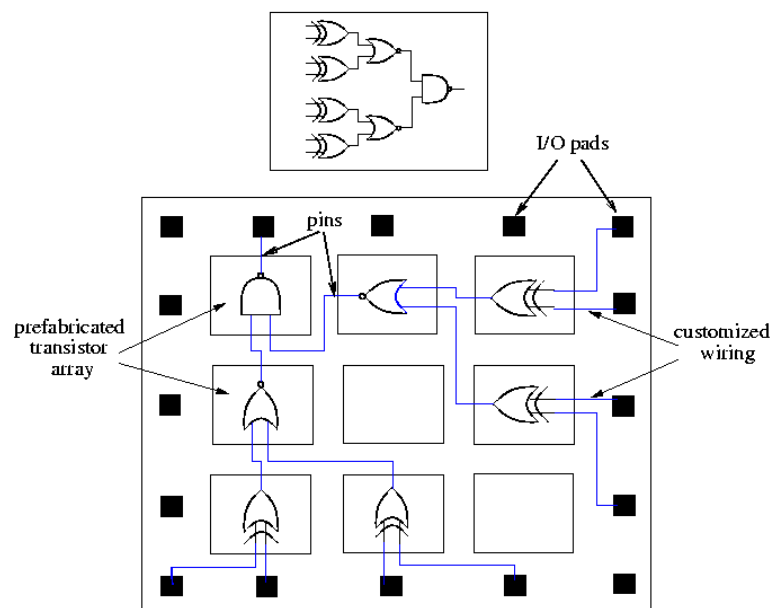


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Gate Array Design Style

- ◆ Prefabricates a transistor array
- ◆ Needs wiring customization to implement logic



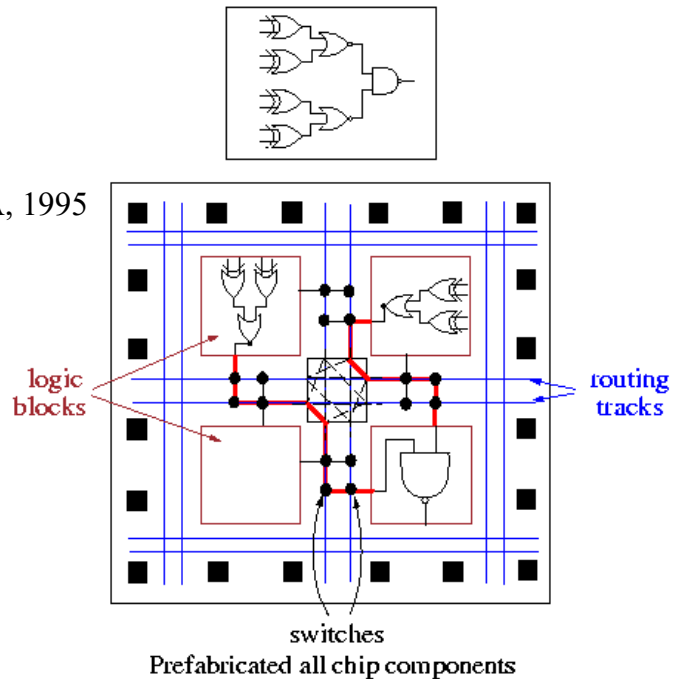
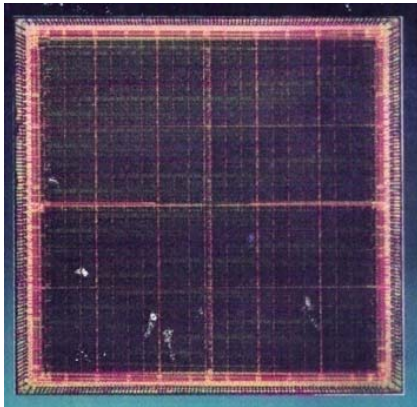
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FPGA Design Style

- ◆ Logic and interconnects are both prefabricated.
- ◆ Illustrated by a symmetric array-based FPGA
- ◆ Another example:

Lucent Technologies 15K ORCA FPGA, 1995

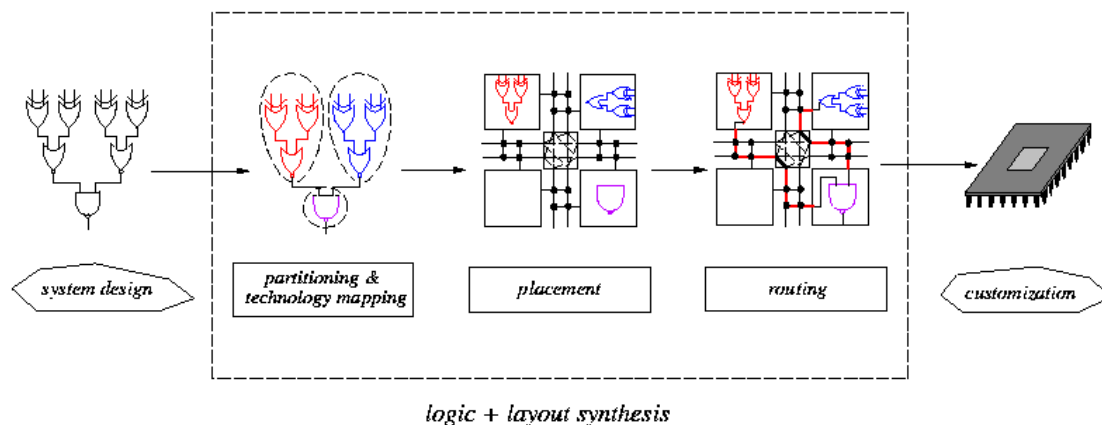


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FPGA Design Process

- ◆ Illustrated by a symmetric array-based FPGA
- ◆ No fabrication is needed



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Comparisons of Design Styles

	Full custom	Standard cell	Gate array	FPGA	SPLD
Cell size	variable	fixed height*	fixed	fixed	fixed
Cell type	variable	variable	fixed	programmable	programmable
Cell placement	variable	in row	fixed	fixed	fixed
Interconnections	variable	variable	variable	programmable	programmable

* Uneven height cells are also used.

	Full custom	Standard cell	Gate array	FPGA	SPLD
Fabrication time	---	--	+	+++	++
Packing density	+++	++	+	--	---
Unit cost in large quantity	+++	++	+	--	--
Unit cost in small quantity	---	--	+	+++	++
Easy design and simulation	---	--	-	++	+
Easy design change	---	--	-	++	++
Accuracy of timing simulation	-	-	-	+	++
Chip speed	+++	++	+	-	--

+ desirable; - not desirable

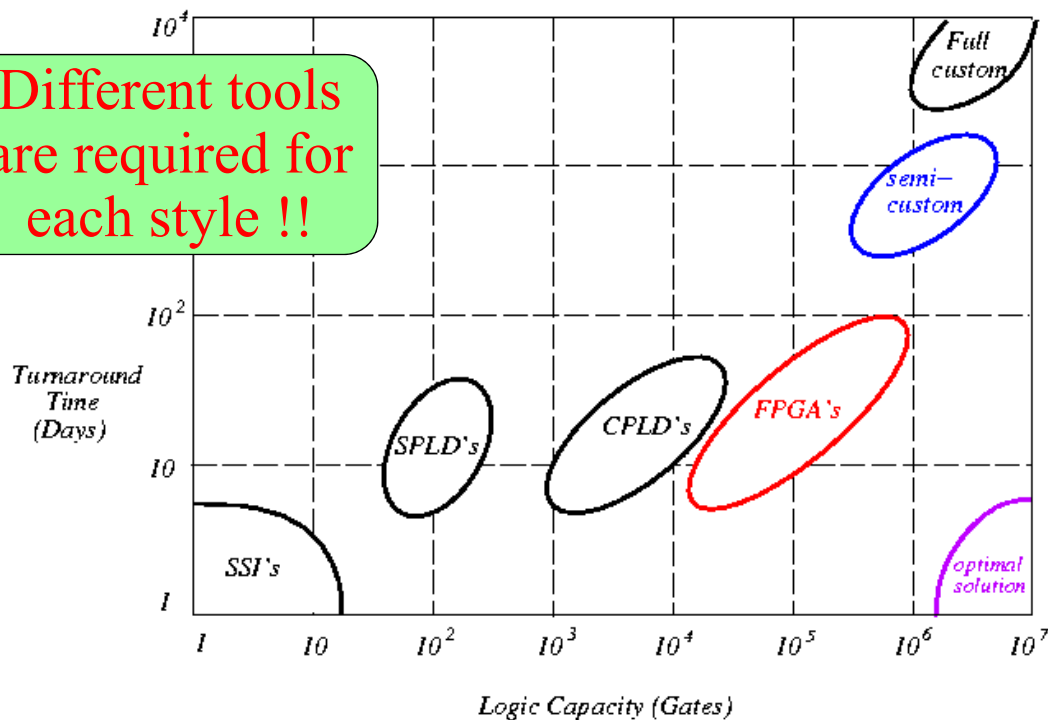


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Design Style Trade-Offs

Different tools are required for each style !!



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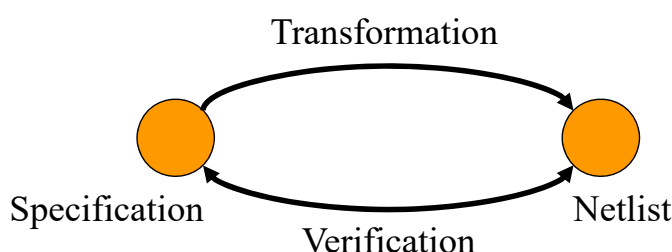


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What is Verification ?

- ◆ A process used to demonstrate the functional correctness of a design
- ◆ To making sure that you are indeed implementing what you want
- ◆ To ensure that the result of some transformation is as expected



Source : “Writing Test Benches – Functional Verification of HDL Models” by Janick Bergeron, KAP, 2000.



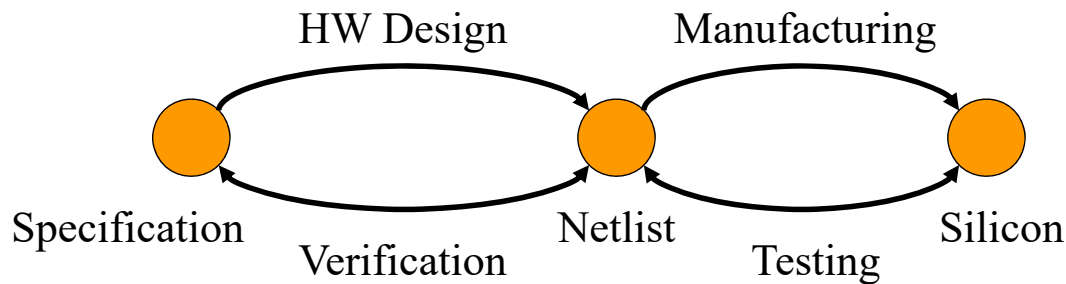
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Testing v.s. Verification

◆ Testing verifies manufacturing

- Verify that the design was **manufactured correctly**



Source : "Writing Test Benches – Functional Verification of HDL Models" by Janick Bergeron, KAP, 2000.



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When is Verification Complete ?

◆ Some answers from real designers:

- When we run out of time or money
- When we need to ship the product
- When we have exercised each line of the HDL code
- When we have tested for a week and not found a new bug
- ***We have no idea!!***

◆ Designs are often too complex to ensure full functional coverage

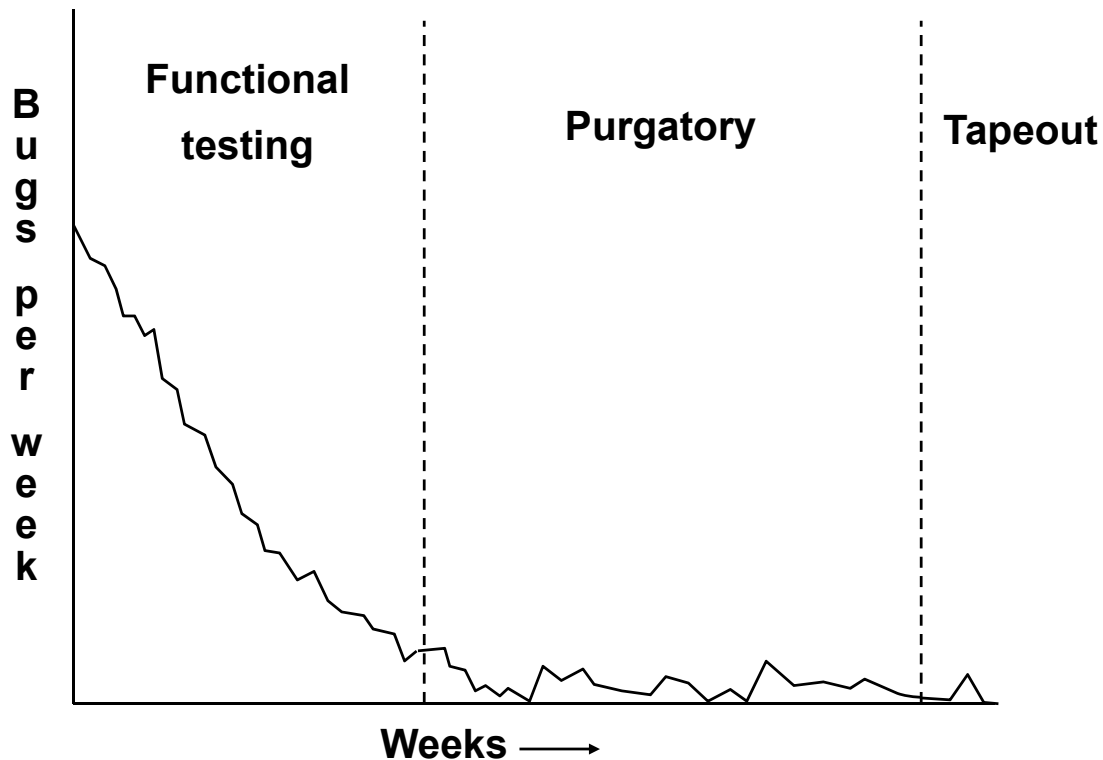
- The number of possible vectors greatly exceeds the time available for test



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Typical Verification Experience



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The Famous Pentium Bug

- ◆ Summary of the Pentium division bug
 - Pentium was Intel's mainstream microprocessor
 - 3.3 Million transistors
 - Early versions all had error in floating point division hardware
 - 5 missing transistors, fixed with change to single mask
 - Disclosed largely via Internet
 - Intel ultimately offered replacements to everyone
 - \$475 Million charge from 4Q94 revenue



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Why Did not Intel Discover it ?

◆ Standard steps in verifying design

- Simulate many cases on high-level software model
- Simulate/emulate final logic design
 - Hardware emulators costing \$Millions
 - Run complete chip model at $\sim 100\text{Hz}$ ($< 10^{-6}$ X real time)
- Run tests on initial production chips
 - Feasible to run billions of tests
 - Should have caught error here
- 1 trillion (10^{12}) test vectors for Pentium chip

◆ Observations

- Hard to test all aspects of such a complex system

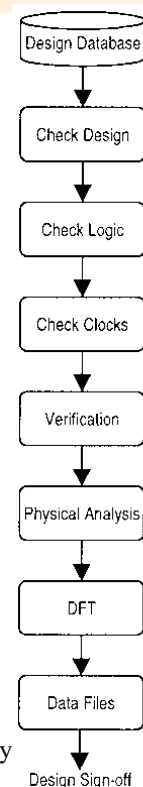


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Design Sign-off

- ◆ Sign-off is the final step in the design process
- ◆ It determines whether the design is ready to be taped out for fabrication
- ◆ No corrections can be made after this step
- ◆ The design team needs to be confident that the design is 100% correct
 - Many items need to be checked
- ◆ Many verification tools are involved at each step in the sign-off flow



Ref : "System-on-a-chip Verification – Methodology and Techniques" by P. Rashinkar, etc., KAP, 2001.



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P.50

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Prototyping

- ◆ Verify designs using real hardware
 - FPGA, emulator
- ◆ Better throughput in handling complex designs
- ◆ Software-driven verification
 - Verify SW using HW
- ◆ Interfaced with real HW components
- ◆ May have a little performance degradation
- ◆ May have capacity limitation
- ◆ Poor debugging capability
- ◆ High cost to fix design problems



Limited Production

- ◆ Even after robust verification process and prototyping, it's still not guaranteed to be bug-free
- ◆ Engineering samples
- ◆ A limited production for new macro is necessary
 - 1 to 4 customers
 - Small volume
 - Reducing the risk of supporting problems
- ◆ Same as real cases but more *expensive*
- ◆ Only used as the final check before mass production

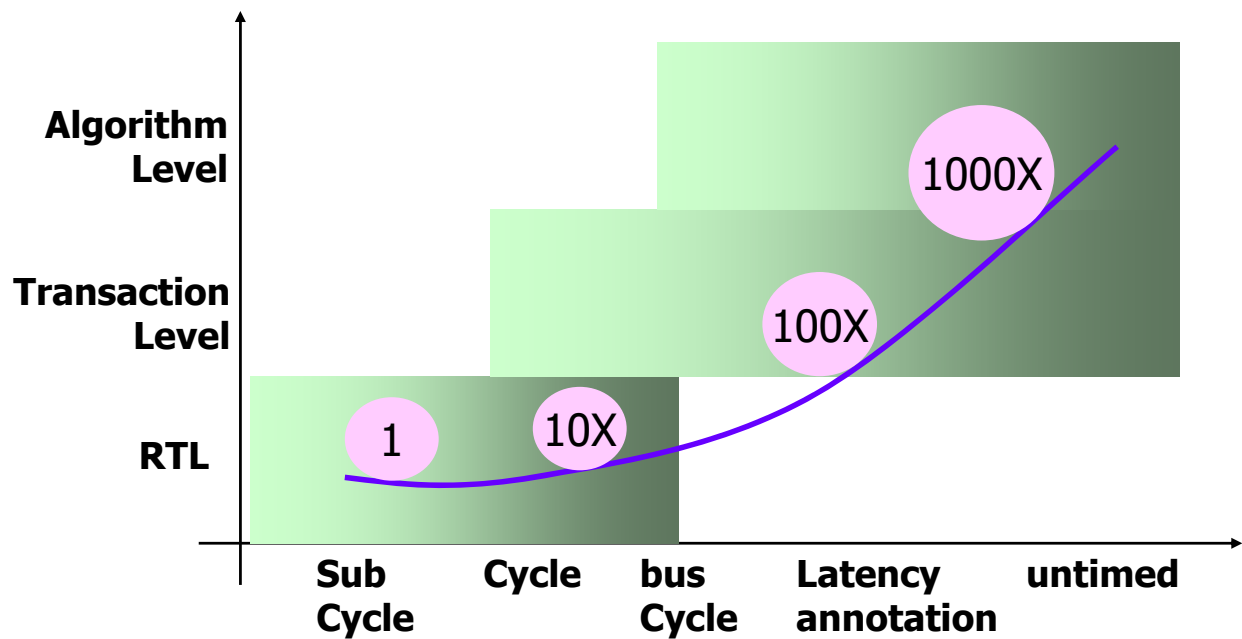


HW/SW Co-Simulation

- ◆ Couple a software execution environment with a hardware simulator
- ◆ Simulate the system at higher levels
 - Software normally executed on an **Instruction Set Simulator** (ISS)
 - A **Bus Interface Model** (BIM) converts software operations into detailed pin operations
- ◆ Allows earlier system integration
- ◆ Start software development 6 months earlier
- ◆ Provide a significant performance improvement for system verification
 - Simulate 100x~1000x faster than RTL



Verification Speed



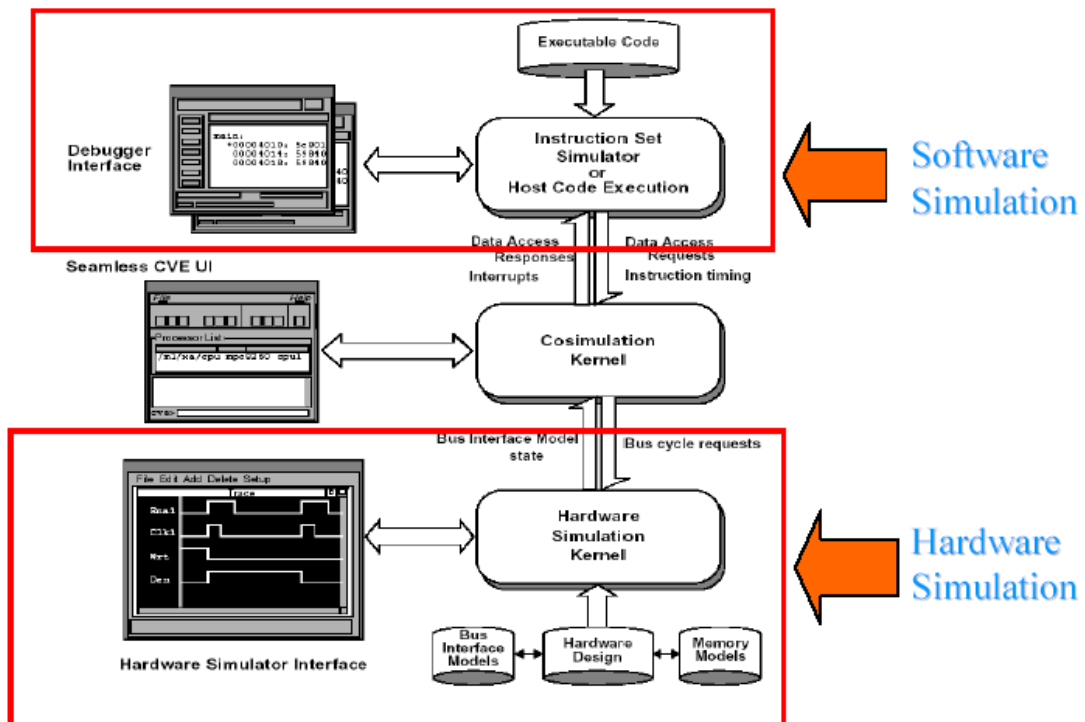
Reference : Synopsys



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P.55

Many Available Tools for Co-Sim.



Reference : Mentor Graphics



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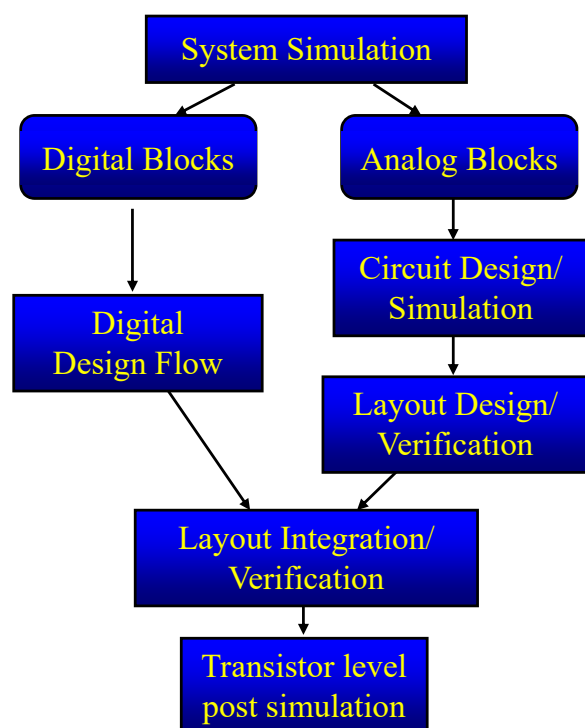
P.56

Outline

- ◆ Moving to SOC
- ◆ CAD in SOC Design
- ◆ Solutions for Verification Problems
- ◆ Solutions for Integration Problems
 - Hardware v.s. software
 - Digital circuits v.s. analog circuits
- ◆ Solutions for DSM Problems



Conventional MS Design Approach



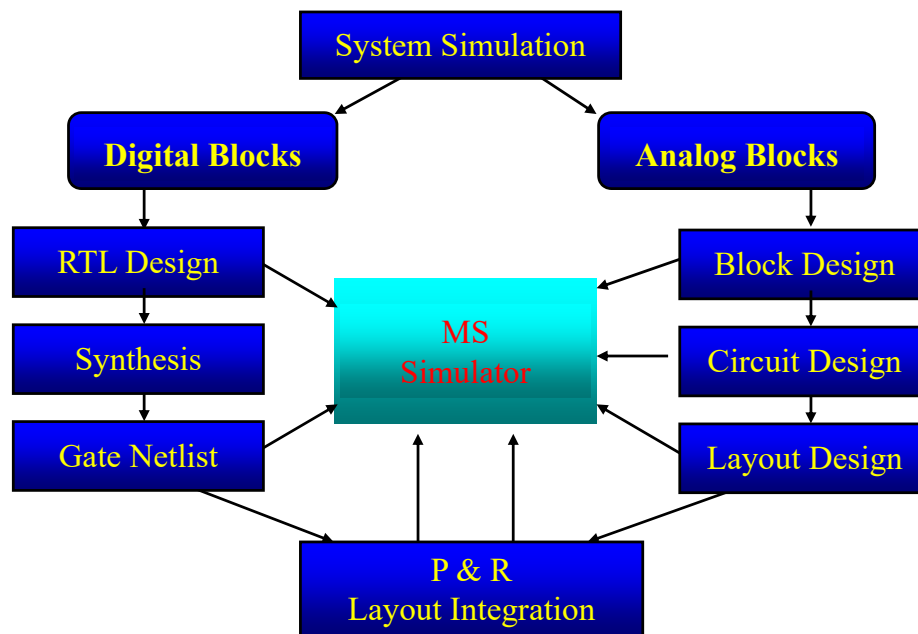
- ◆ Design and simulate digital and analog circuits separately
 - May miss the effects between each other
- ◆ Can perform co-simulation at transistor level only
 - High complexity
 - Too slow



Top-Down MS Design Flow

◆ Starting from **behavioral models**

- Can check whole system behavior in advance



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P.59

Behavioral Modeling

◆ A mathematical model written in **Hardware Description Language**

- Verilog-A
 - Verilog-AMS
 - VHDL-A
 - VHDL-AMS
 -
- ◆ Emulate circuit block functionality by sensing and responding to circuit conditions



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P.60

Why Behavioral Simulation ?

- ◆ **Faster** simulation
- ◆ Can verify circuit blocks at **behavioral level**
- ◆ Allow **system simulation** with pin-accurate block models
 - Easier to verify the system integration
- ◆ Digital blocks can also be simulated together in a mixed-signal environment
- ◆ Whole chip simulation becomes feasible
- ◆ Have to change the original methodology of analog designers
 - Hard !!

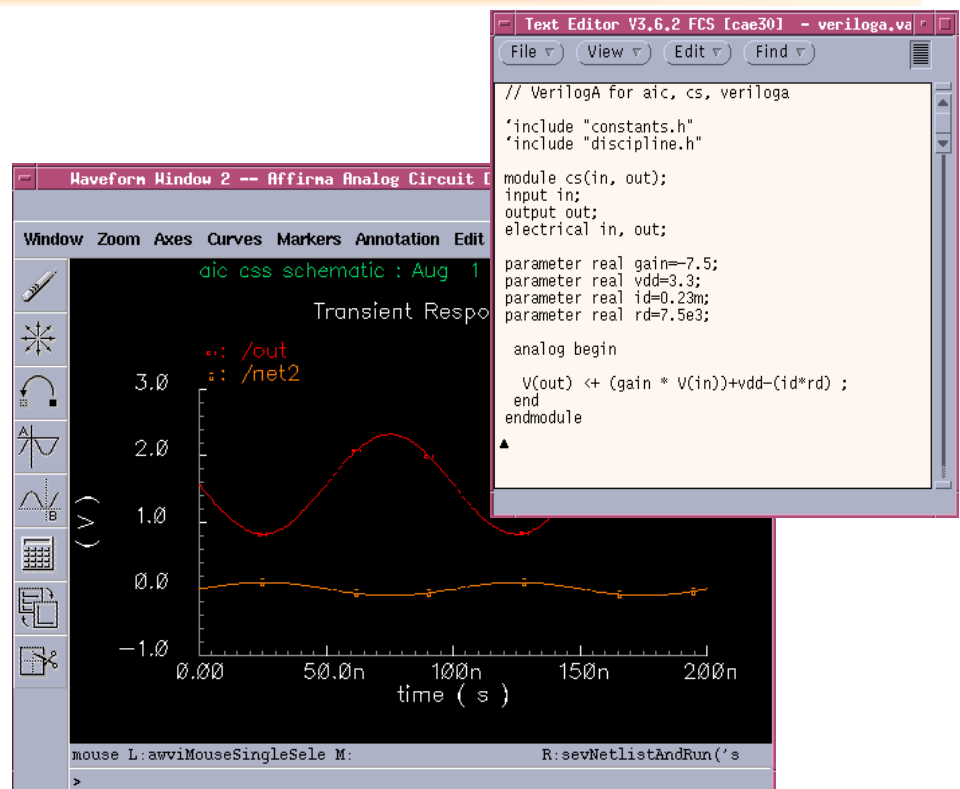


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P.61

Available Simulation Environment

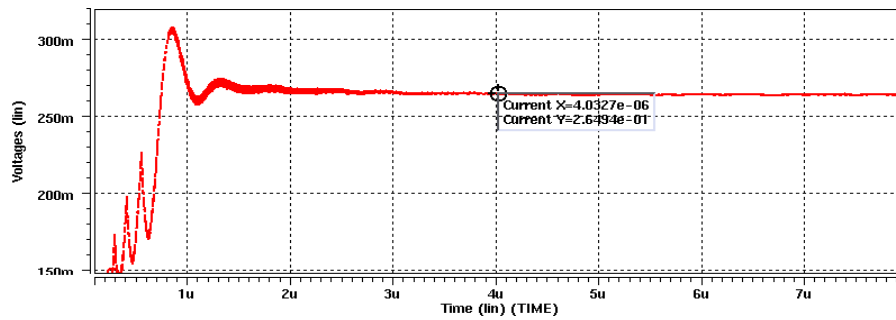
- ◆ Cadence
- ◆ Antrim
- ◆ Mentor
- ◆ Synopsys
- ◆



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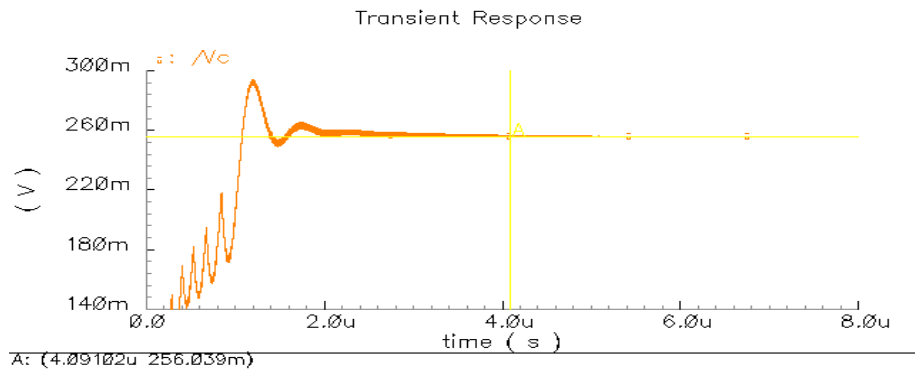
P.62

Waveform of PLL Locking



HSpice

Lock time:
4.03 us
Lock voltage:
0.265 v
Simulation time:
22405 sec



Verilog-A

Lock time:
4.09 us
Lock voltage:
0.256 v
Simulation time:
336 sec



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P.63

Outline

- ◆ Moving to SOC
- ◆ CAD in SOC Design
- ◆ Solutions for Verification Problems
- ◆ Solutions for Integration Problems
- ◆ **Solutions for DSM Problems**

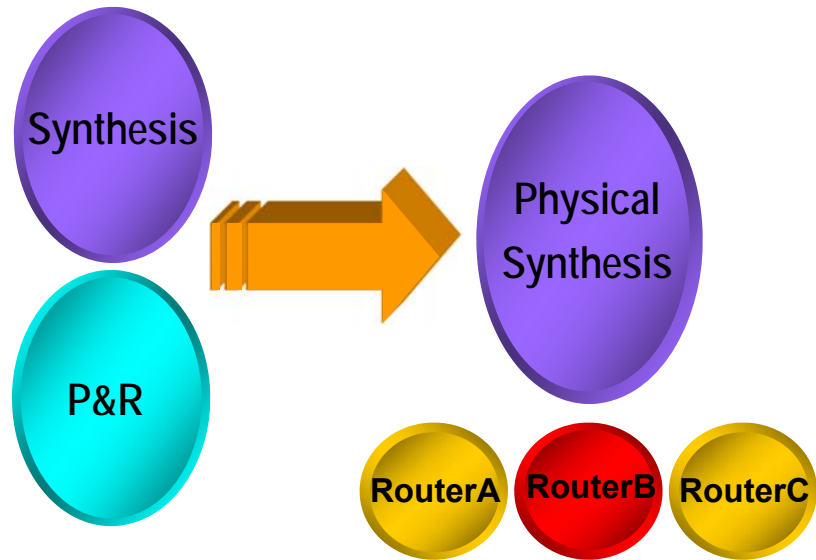


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Physical Synthesis

- ◆ “Physical synthesis” is a new concept to solve timing closure problem at the synthesis step
- ◆ Integrate placement engine with logic synthesis to get more accurate wire length estimation
 - From outer loop to inner loop ??
- ◆ Not only database but also timing engine are integrated
 - Consistency makes better results

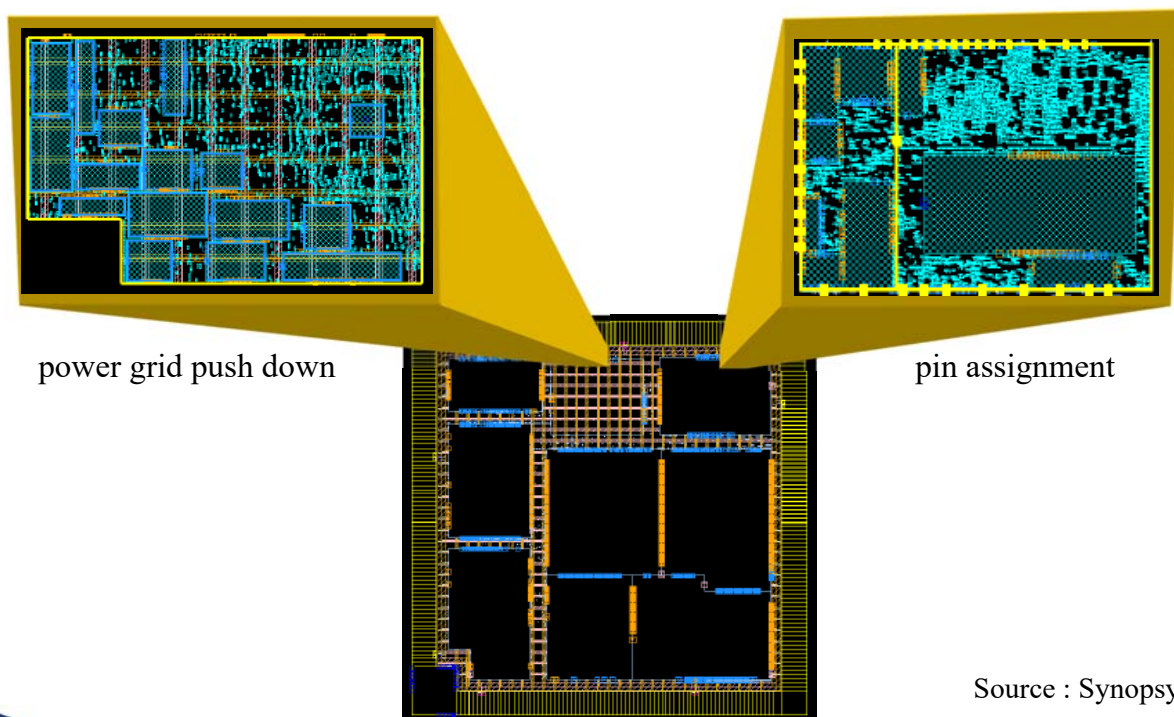


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Hierarchical P&R

- ◆ Hierarchical methodologies are the key to cope high complexity !!



Source : Synopsys

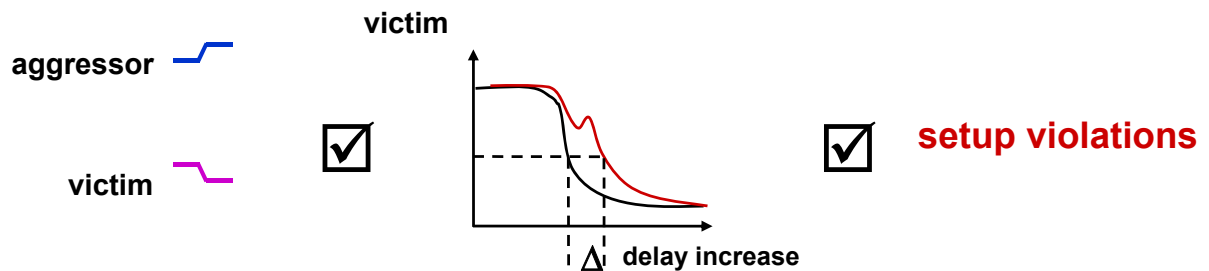


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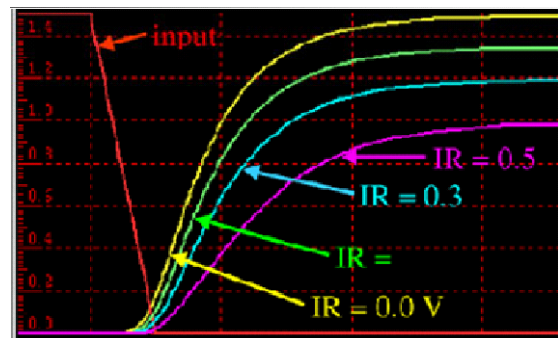
P.66

Extra Checks for SI & IR-Drop

- ◆ Must be checked for signal integrity (SI) problems before manufacturing



- ◆ IR-drop is also an serious problem due to large peak current



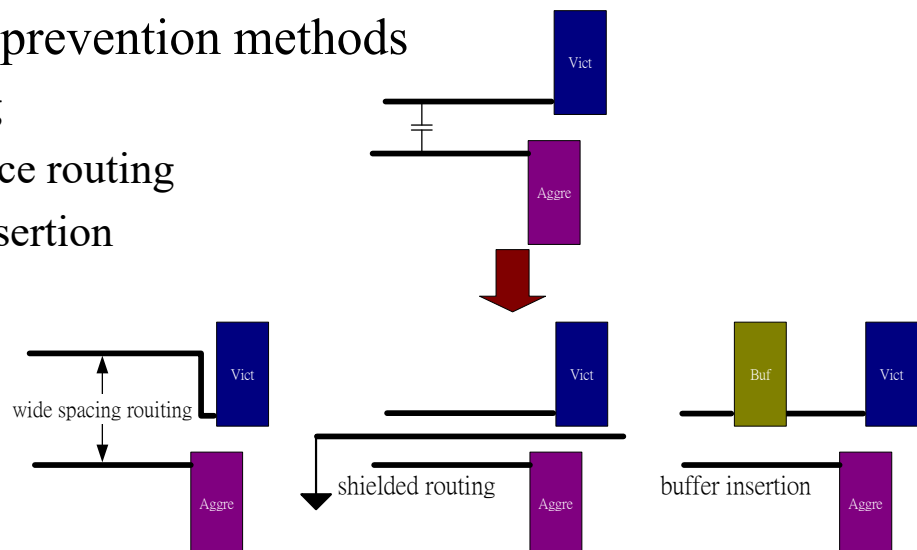
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P.67

SI & IR-Drop Prevention

- ◆ Typical SI prevention methods

- Shielding
- Wide space routing
- Buffer insertion



- ◆ To prevent IR-drop problem, we have to identify the *current density* problems with power analysis

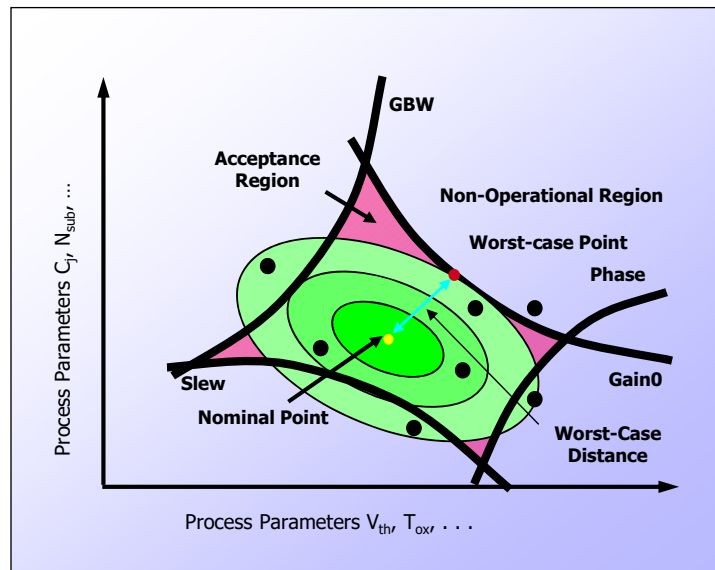


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Solve Reliability Problems

- ◆ There are still some problems that can make chip fail after a period of time
 - Electron migration
 - Hot electron
 - Process variation
 -
- ◆ Use design-for-manufacturing (DFM) or design-for-Yield (DFY) techniques to obtain suitable design margins



Source : ChipMD



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P.69

Conclusions



工欲善其事
必先利其器 !!



- ◆ SoC is really a big challenge for IC designers
- ◆ Design methodology requires a big change
 - Reusing existing IPs and platforms is the key
- ◆ More powerful tools are essential to solve those difficult design problems
- ◆ **EDA – Where Electronics Begins**



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P.70